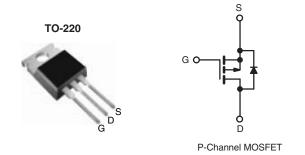


Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	- 100			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = - 10 V	0.60		
Q _g (Max.) (nC)	18			
Q _{gs} (nC)	3.0			
Q _{gd} (nC)	9.0			
Configuration	Single			



FEATURES

- · Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- P-Channel
- 175 °C Operating Temperature
- · Fast Switching
- · Ease of Paralleling
- · Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRF9520PbF
Leau (FD)-nee	SiHF9520-E3
SnPb	IRF9520
SIFD	SiHF9520

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, ur	nless otherw	ise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	- 100	V	
Gate-Source Voltage			V_{GS}	± 20		
Continuous Drain Current	V _{GS} at - 10 V	T _C = 25 °C		- 6.8	А	
		T _C = 100 °C	ID	- 4.8		
Pulsed Drain Current ^a			I _{DM}	- 27	1	
Linear Derating Factor				0.40	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	300	mJ	
Repetitive Avalanche Currenta			I _{AR}	- 6.8	Α	
Repetitive Avalanche Energy ^a			E _{AR}	6.0	mJ	
Maximum Power Dissipation	T _C = 25 °C		P _D	60	W	
Peak Diode Recovery dV/dtc			dV/dt	- 5.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 175	00	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d	°C	
Mounting Torque	6.00.0*1	C 00 av M0 aava		10	lbf ⋅ in	
	6-32 or M3 screw			1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = -25 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 9.7 \,^{\circ}\text{mH}$, $R_G = 25 \,^{\circ}\Omega$, $I_{AS} = -6.8 \,^{\circ}\Lambda$ (see fig. 12).
- c. $I_{SD} \le -6.8 \text{ A}$, dl/dt $\le 110 \text{ A/}\mu\text{s}$, $V_{DD} \le V_{DS}$, $T_{J} \le 175 ^{\circ}\text{C}$.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



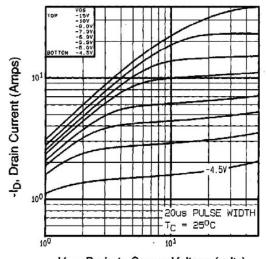
THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.5		

PARAMETER	SYMBOL	TEST	TEST CONDITIONS		TYP.	MAX.	UNIT
Static					•		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$		- 100	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = - 1 mA		- 0.10	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	' _{GS} , I _D = - 250 μA	- 2.0	-	- 4.0	V
Gate-Source Leakage	I _{GSS}	V	V _{GS} = ± 20 V		-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		V _{DS} = - 100 V, V _{GS} = 0 V V _{DS} = - 80 V, V _{GS} = 0 V, T _J = 150 °C		-	- 100 - 500	μА
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = - 10 V	I _D = - 4.1 A ^b	-	-	0.60	Ω
Forward Transconductance	9 _{fs}	V _{DS} = - :	50 V, I _D = - 4.1 A ^b	2.0	-	-	S
Dynamic					•		
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = -25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	390	-	pF
Output Capacitance	C _{oss}			-	170	-	
Reverse Transfer Capacitance	C _{rss}			-	45	-	
Total Gate Charge	Qg			-	-	18	nC
Gate-Source Charge	Q _{gs}	V _{GS} = - 10 V	I _D = -6.8 A, V _{DS} = -80 V, see fig. 6 and 13 ^b	-	-	3.0	
Gate-Drain Charge	Q _{gd}	1	see lig. 6 and 13	-	-	9.0	
Turn-On Delay Time	t _{d(on)}		V _{DD} = - 50 V, I _D = - 6.8 A,		9.6	-	ns ns
Rise Time	t _r	V _{DD} = -			29	-	
Turn-Off Delay Time	t _{d(off)}	$R_G = 18 \Omega$, $R_D = 7.1 \Omega$, see fig. 10^b		-	21	-	
Fall Time	t _f			-	25	-	
Internal Drain Inductance	L_{D}	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s				•		
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	- 6.8	_
Pulsed Diode Forward Current ^a	I _{SM}			ı	-	- 27	A
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = -6.8 \text{A}, V_{GS} = 0 \text{V}^b$		-	-	- 6.3	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25$ °C, $I_F = -6.8$ A, $dI/dt = 100$ A/ μ s ^b		-	98	200	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.33	0.66	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-		-on is dor	ninated by	y L _S and	L _D)

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μs ; duty cycle \leq 2 %.

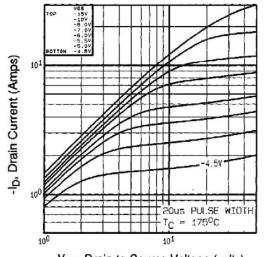


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



-V_{DS}, Drain-to-Source Voltage (volts)

Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C



- V_{DS} , Drain-to-Source Voltage (volts) Fig. 2 - Typical Output Characteristics, T_C = 175 °C

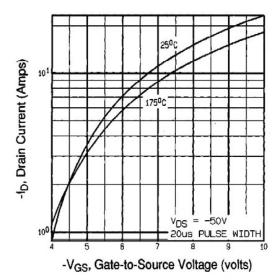
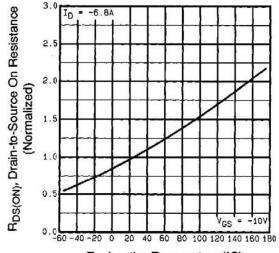


Fig. 3 - Typical Transfer Characteristics



T_J, Junction Temperature (°C)

Fig. 4 - Normalized On-Resistance vs. Temperature



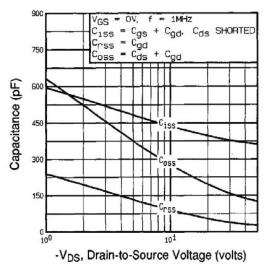


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

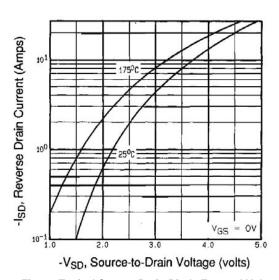


Fig. 7 - Typical Source-Drain Diode Forward Voltage

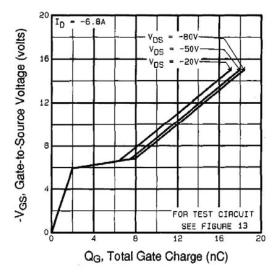


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

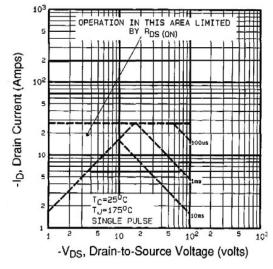


Fig. 8 - Maximum Safe Operating Area



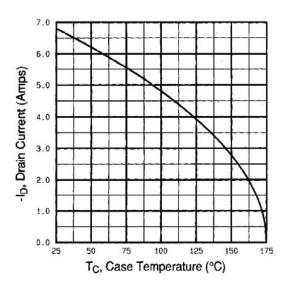


Fig. 9 - Maximum Drain Current vs. Case Temperature

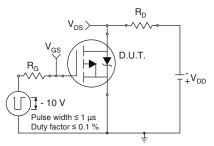


Fig. 10a - Switching Time Test Circuit

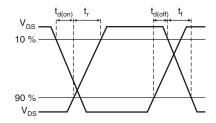
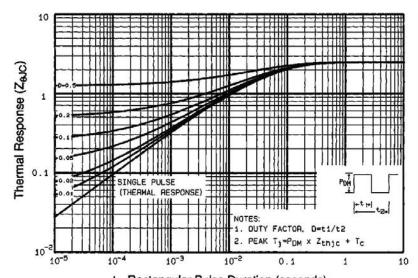


Fig. 10b - Switching Time Waveforms



 $t_1,\, \text{Rectangular Pulse Duration (seconds)} \\ \text{Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case} \\$

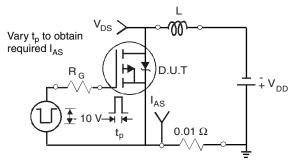


Fig. 12a - Unclamped Inductive Test Circuit

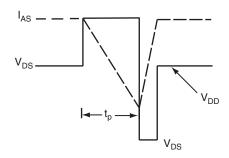


Fig. 12b - Unclamped Inductive Waveforms



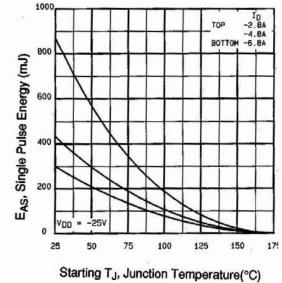


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

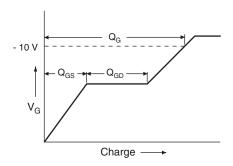


Fig. 13a - Basic Gate Charge Waveform

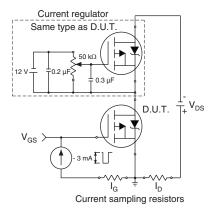
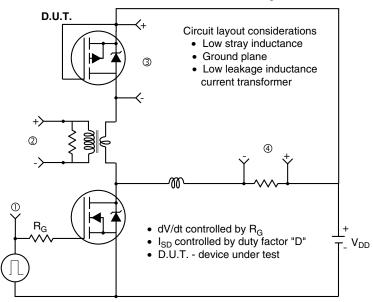


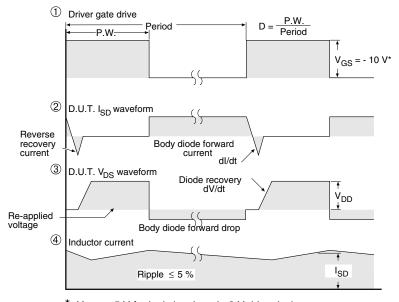
Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



• Compliment N-Channel of D.U.T. for driver



* V_{GS} = - 5 V for logic level and - 3 V drive devices

Fig. 14 - For P-Channel

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